

OptiMOS™-5 Power-Transistor







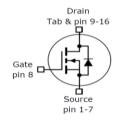
Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Normal Level
- Extended qualification beyond AEC-Q101
- · Enhanced electrical testing
- Robust design
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green product (RoHS compliant)
- 100% Avalanche tested

Product	Summary

V_{DS}	80	V
R _{DS(on)}	1.2	mΩ
I _D	300	Α





Туре	Package	Marking
IAUS300N08S5N012T	PG-HDSOP-16-2	5N08012

Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	V _{GS} =10 V, Chip limitation ^{1,2)}	400	А
		V _{GS} =10V, DC current ³⁾	300	
		T_{a} =85 °C, V_{GS} =10 V, R_{thJA} on 2s2p ^{2,4)}	117	
Pulsed drain current ²⁾	I _{D,pulse}	$T_{\rm C}$ =25 °C, $t_{\rm p}$ = 100 μs	1450	
Avalanche energy, single pulse ²⁾	E _{AS}	/ _D =150 A	817	mJ
Avalanche current, single pulse	I _{AS}	-	300	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	T _C =25 °C	375	W
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$	-	-55 +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	Тор	-	-	0.4	K/W
		Bottom (Pin 1-7)	-	9	-	
		Bottom (Pin 9-16)	-	3	-	
Thermal resistance, junction - ambient ⁴⁾	R_{thJA}	Тор	-	2.8	-	
	, thJA	Bottom (through PCB)	-	40	-	

Electrical characteristics, at T_i =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA	80	1	1	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 275 \mu{\rm A}$	2.2	3	3.8	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS} = 80 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	0.1	1	μΑ
		$V_{\rm DS}$ =50 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =85 °C ²⁾	-	1	20	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =6 V, I _D =75 A	-	1.4	1.8	mΩ
		V _{GS} =10 V, I _D =100 A	-	1.0	1.2	
Gate resistance ²⁾	R_{G}	-	-	1.5	-	Ω



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	12500	16250	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz	-	2000	2600	*
Reverse transfer capacitance	C _{rss}		-	86	130	
Turn-on delay time	t _{d(on)}		-	31	-	ns
Rise time	t _r	V _{DD} =40 V, V _{GS} =10 V,	-	19	-	1
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =100 A, $R_{\rm G}$ =3.5 Ω	-	69	-	
Fall time	t_{f}]	-	55	-	1
Gate Charge Characteristics ²⁾ Gate to source charge	Q _{gs}	<u> </u>		56	73	nC
Gate to drain charge	Q _{gd}	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V	<u> </u>	37	56	-
Gate charge total	Q _g		-	178	231	<u> </u>
Gate plateau voltage	V _{plateau}		-	4.5	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T _C =25 °C	-	-	300	А
Diode pulse current ²⁾	I _{S,pulse}	$T_{\rm C}$ =25 °C, $t_{\rm p}$ = 100 μs	-	-	2300	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =100 A, T _j =25 °C	-	0.9	1.2	V
Reverse recovery time ²⁾	t _{rr}	V _R =40 V, I _F =50A, di _F /dt=100 A/µs	-	86	-	ns
Reverse recovery charge ²⁾	Q _{rr}		_	177	_	nC

¹⁾ Practically the current is limited by the overall system design including the customer-specific PCB.

²⁾ The parameter is not subject to production testing – specified by design.

³⁾ Current is limited by the bondwires.

 $^{^{4)}}$ Device on a four-layer 2s2p FR4 PCB with topside cooling. Thermal insulation material is 100 μ m thick and has a conductivity of 0.7 W/mK. Top surface of heat sink is fixed at ambient temperature. Bottom surface of PCB is left at free convection. Values may vary depending on the customer-specific design.



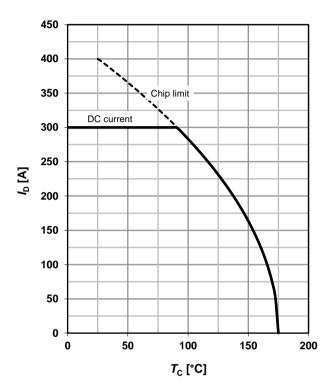
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

300 300 100 100 0 50 100 150 200 T_C [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



3 Safe operating area

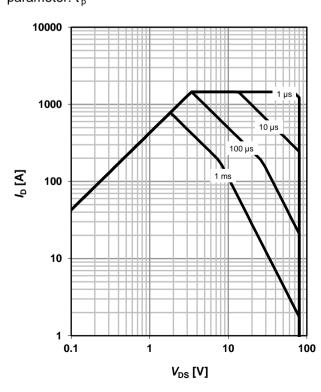
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

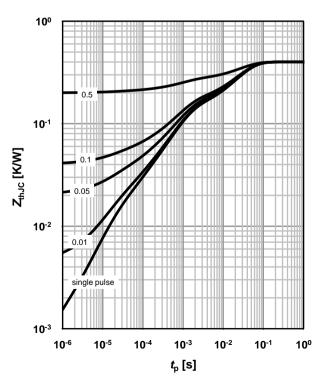
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_{p})$$

parameter: $D=t_p/T$



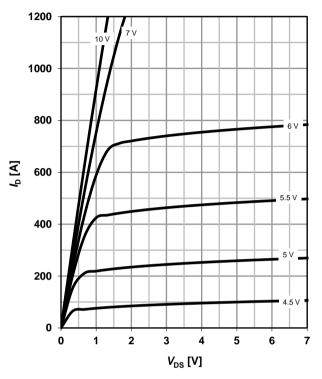




5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

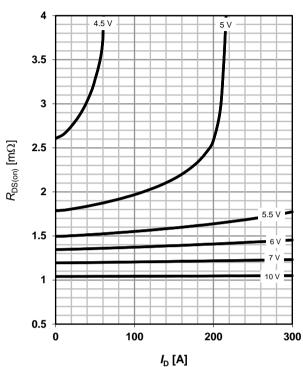
parameter: V_{GS}



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

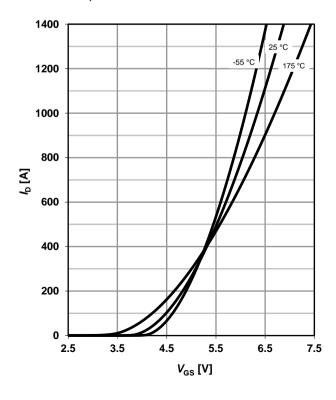
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$

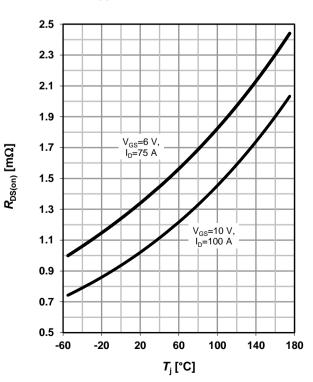
parameter: $T_{\rm j}$



8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j)$

parameter: I_D , V_{GS}





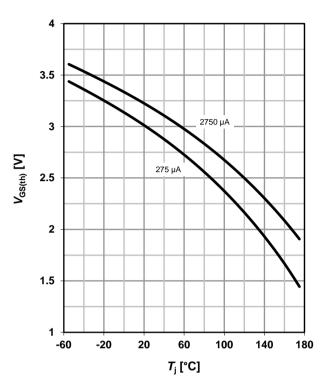
9 Typ. gate threshold voltage

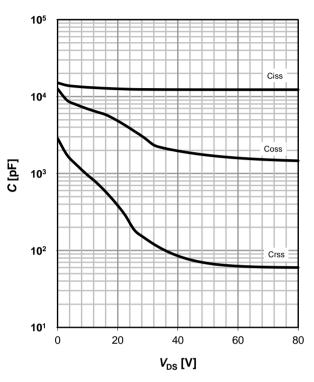
 $V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$





11 Typical forward diode characteristics

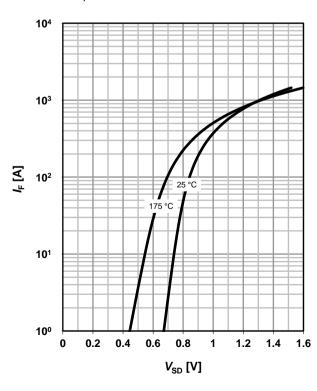
 $I_F = f(V_{SD})$

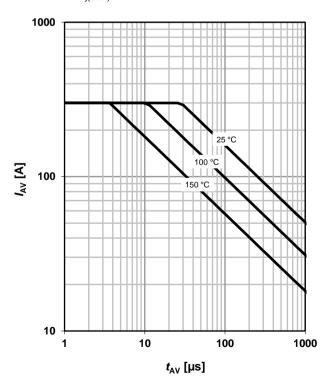
parameter: $T_{\rm j}$

12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{i(start)}







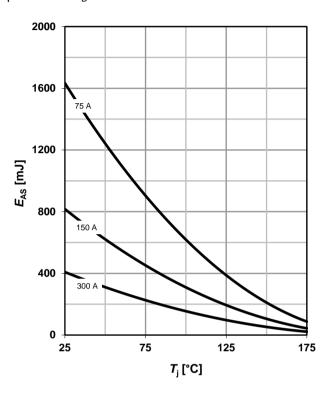
13 Typical avalanche energy

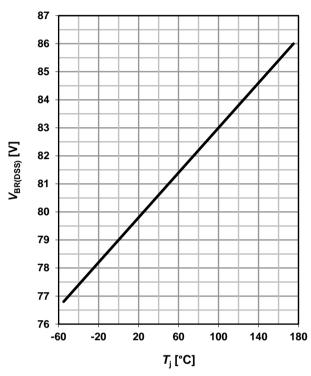
 $E_{AS} = f(T_i)$

parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_{D_{typ}} = 1 \text{ mA}$$

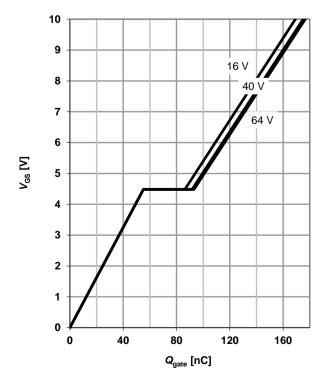




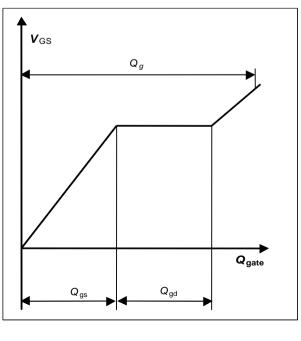
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 100 A pulsed$

parameter: V_{DD}

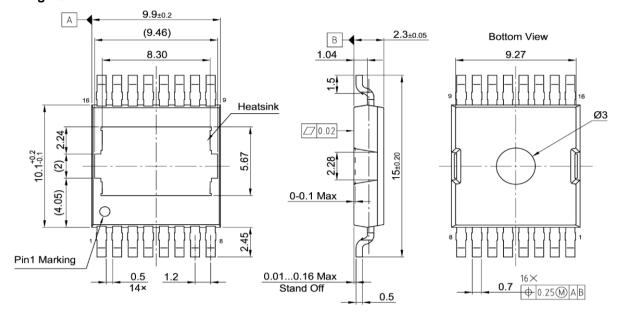


16 Gate charge waveforms



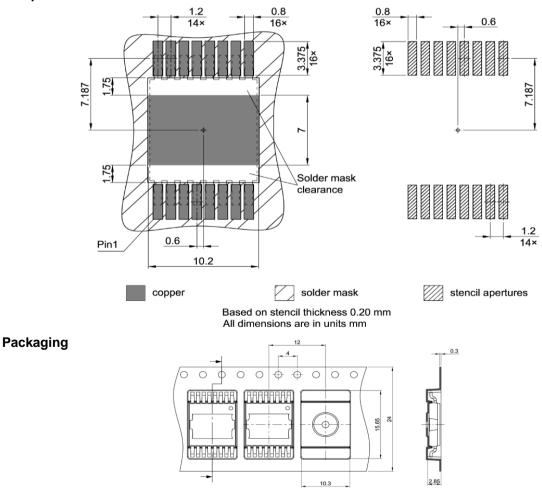


Package Outline



All metal surfaces tin plated except area of cut and heatsink
All dimensions are in units mm
The drawing is in compliance with ISO 128-30, Projection Method 1 [•]

Footprint





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Revision History

Version	Date	Changes	
Version 1.0	01.10.2020	Final Datasheet	